

Nanometrics to Participate in the 8th Annual CEO Investor Summit

Investor Event Held Concurrently with SEMICON West 2016 in San Francisco

MILPITAS, Calif., June 22, 2016 (GLOBE NEWSWIRE) -- Nanometrics Incorporated (Nasdaq:NANO), a leading provider of advanced process control systems, today announces that company management is scheduled to participate in the 8th Annual CEO Summit, a preeminent investor and analyst event held concurrently with the SEMICON West trade show in San Francisco.

The event will take place on Wednesday, July 13th, 2016, from 8:30am until 3:00pm PDT, with Nanometrics management scheduled to host meeting sessions from 12:30pm until 3:00pm. Presentation materials utilized during the event will be made available on Nanometrics' website at www.nanometrics.com.

About the 8th Annual CEO Summit

The CEO Summit is an accredited investor and publishing research analyst event that is held concurrently with SEMICON West and Intersolar 2016 in San Francisco. The event is hosted by executive management from participating companies and will feature a "round-robin" format consisting of small group meetings, each 30 minutes in duration. During the event, investors and analysts will have the opportunity to meet with up to 10 of the 20 management teams during the 30-minute group meeting sessions, as well as opportunities to meet with additional management teams during the breakfast and lunch networking sessions.

The 20 management teams collectively hosting the 2016 CEO Summit include: Axcelis (ACLS), Aehr Test (AEHR), Brooks (BRKS), Camtek (CAMT), Cabot Micro (CCMP), Cohu (COHU), Electro Scientific (ESIO), Exar (EXAR), FormFactor (FORM), inTEST (INTT), Intevac (IVAC), MKS Instruments (MKS), Nanometrics (NANO), Rudolph (RTEC), Soitec (SOIT), Tessera (TSRA), Tower (TSEM), Ultra Clean (UCTT), Ultratech (UTEK) and Xcerra (XCRA). Sponsors of the event include Cowen & Co and Stifel.

The CEO Summit is by invitation only and is open to accredited investors and publishing research analysts. As space is limited, please RSVP early. Hosts reserve the right to limit attendance as necessary. Last day for registration is July 6, 2016.

While held concurrently with SEMICON West and Intersolar 2016, the event is not affiliated with the show.

RSVP Contacts for 8th Annual CEO Summit 2016

To RSVP for the CEO Summit, please contact either of the Summit's co-chairs.

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About Nanometrics

Nanometrics is a leading provider of advanced, high-performance process control metrology and inspection systems used primarily in the fabrication of semiconductors and other solid-state devices, including sensors, optoelectronic devices, high-brightness LEDs, discretes and data storage components. Nanometrics' automated and integrated metrology systems measure critical dimensions, device structures, topography and various thin film properties, including three-dimensional features and film thickness, as well as optical, electrical and material properties. The company's process control solutions are deployed throughout the fabrication process, from front-end-of-line substrate manufacturing, to high-volume production of semiconductors and other devices, to advanced three-dimensional wafer-level packaging applications. Nanometrics' systems enable advanced process control for device manufacturers, providing improved device yield at reduced manufacturing cycle time, supporting the accelerated product life cycles in the semiconductor and other advanced device markets. The company maintains its headquarters in Milpitas, California, with sales and service offices worldwide. Nanometrics is traded on NASDAQ Global Select Market under the symbol NANO. Nanometrics' website is

<http://www.nanometrics.com>.

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